

# FE-I4

-The New ATLAS Pixel Chip for Upgraded LHC Luminosities-

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(for the FE-I4 Collaboration)

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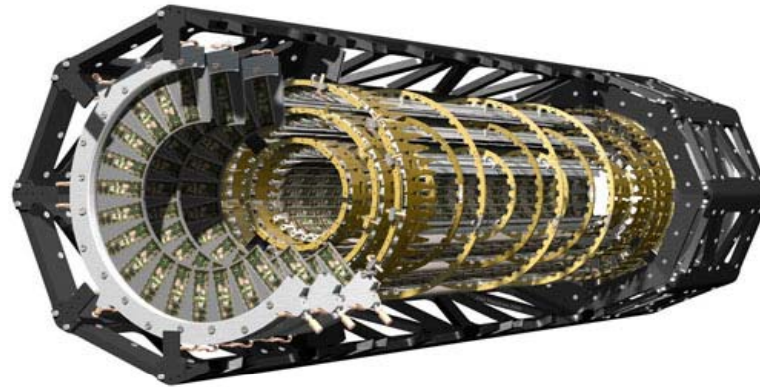
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- Upgrades: IBL / sLHC.
  - FE-I4, new ATLAS pixel FE for IBL & sLHC.
- Analog pixel.
- Digital pixel and digital Double-Column.
- Periphery.
- Yield.
- Conclusion and milestones.

# FE-I4 for IBL & sLHC



Present beam pipe & B-Layer

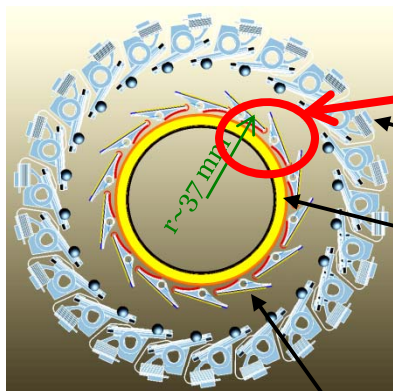


ATLAS Pixel Detector

3 barrel layers / 3 end-caps  
 end-cap:  $z \pm 49.5 / 58 / 65$  cm  
 barrel:  $r \sim 5.0 / 8.8 / 12.2$  cm

- IBL (~2014): inserted layer in current pixel detector.

- sLHC tentative layout (>2017): 4-5 pixel layers, small radii / large(r) radii (note: Discussion on boundary pixel / short strips, ...).



IBL mounted on beam pipe

FE-I4

Existing B-layer

New beam pipe

- All Silicon.
- Long Strips/ Short Strips / Pixels.
- Pixels:

- 2 or 3 fixed layers at 'large' radii (large area at 16 / 20 / 25 cms?)

- 2 removable layers at 'small' radii

# Motivation for Redesign of FE

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- **Need for a new FE?** —→ FE-I3→FE-I4
  - Accommodate higher hit rate (smaller b-layer radius + luminosity increase) → **Architecture based on local memories** (no column-drain mechanism).
  - **Smaller pixel size**: enhanced granularity and reduced cross-section.
  - **Reduced periphery & bigger chip**: higher active area fraction (<75% → ~90%); cost down for sLHC (main driver is flip-chip, costs per chip).  
Big chip a challenge: power (routing, start-up), clk. distrib., yield...
  - **Simple module**: No Module Controller → More digital functions into the FE.
  - **Power efficient design & new concepts**: Analog design for reduced currents; decrease of digital activity (digital logic sharing for neighbor pixels); new powering concepts. 8 metal layers [2 thick Alu.] → Power routing.
- **New technology**: —→ 0.25  $\mu\text{m}$ →130 nm
  - **Higher integration density** for digital circuits, **radiation-hardness** (no Enclosed Layout Transistor), **availability** on timescales of our experiments.

# Some Target Specs for FE-I4

- Rad.-hardness: **>200 MRad** ionizing dose (FE-I3: >50 Mrad).  
Minimal guidelines: **no ELT**, minimal size and guard rings only for analog & sensitive digital circuitry.
- **ToT coded 4 bits.**
- **DC leakage current tolerant to > 100 nA.**

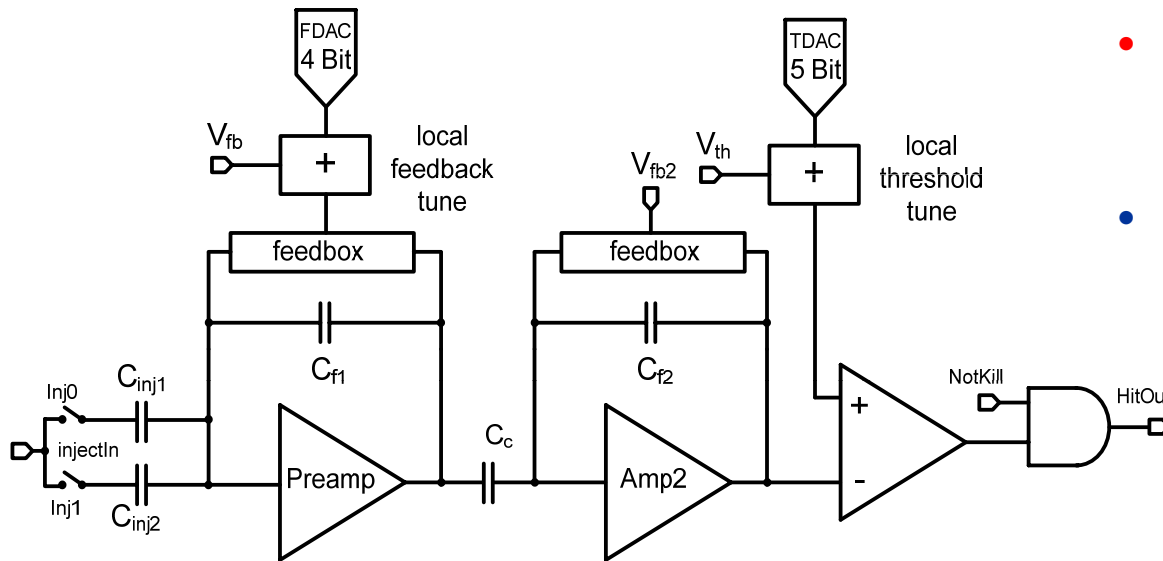
	FE-I3	FE-I4
Pixel Size [ $\mu\text{m}^2$ ]	50×400	50×250
Pixel Array	18×160	80×336
Chip Size [ $\text{mm}^2$ ]	7.6×10.8	20.2×19.0
Active Fraction	74 %	89 %
Analog Current [ $\mu\text{A}/\text{pix}$ ]	26	10
Digital Current [ $\mu\text{A}/\text{pix}$ ]	17	10
Analog Voltage [V]	1.6	1.5
Digital Voltage [V]	2	1.2
pseudo-LVDS out [Mb/s]	40	160

biggest in HEP to date

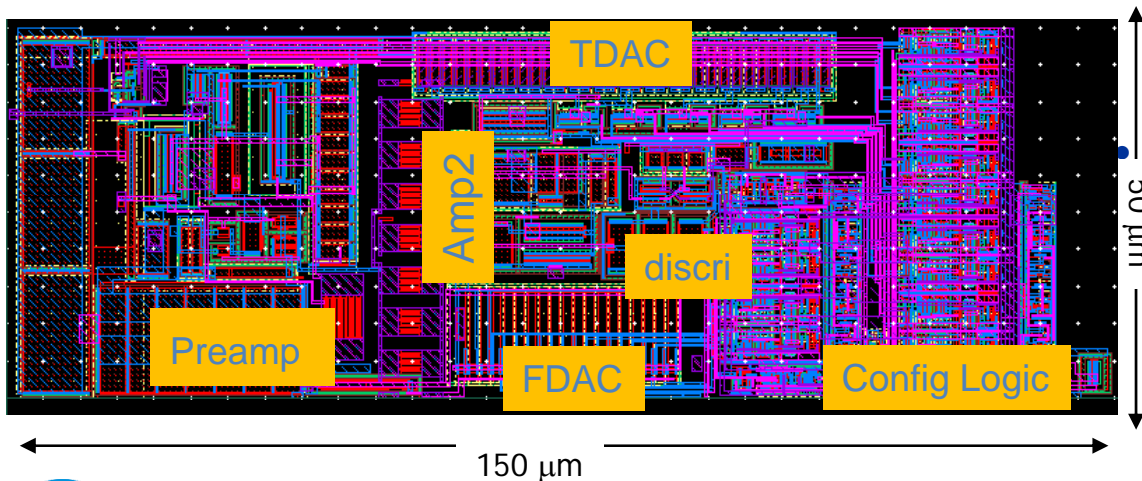
analog / digital power

tuned for IBL occupancy

# Analog Pixel



- In **FE-I4\_prot01** (FE-I4 prototype submitted in 2008):
- **2-stage architecture** optimized for low power, low noise, fast rise time.
  - regul. casc. preamp. nmos input.
  - folded casc. 2<sup>nd</sup> stage pmos input.
  - Additional gain,  $C_c/C_{f2} \sim 6$ .
  - 2<sup>nd</sup> stage decoupled from leakage related DC potential shift.
  - $C_{f1} \sim 17\text{fF}$  ( $\sim 4$  MIPs dyn. range).

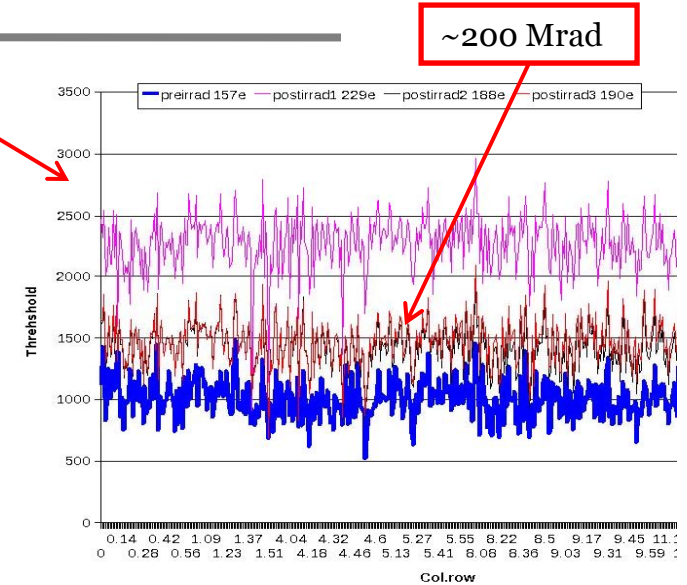
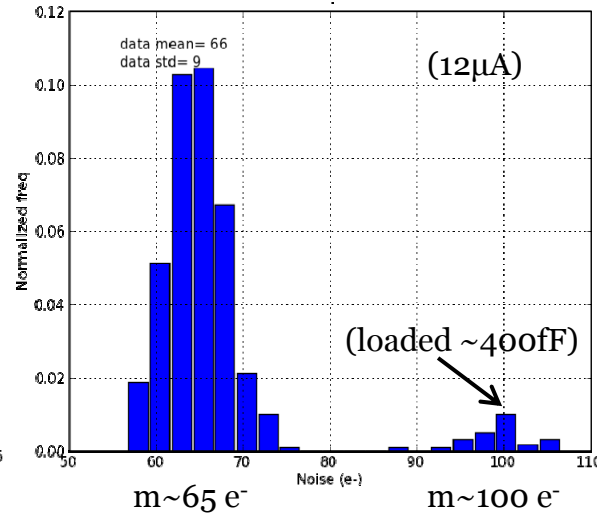
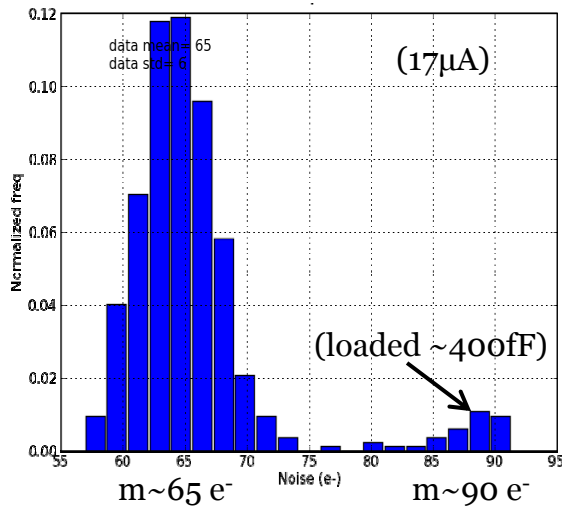


## 12b configuration:

- FDAC: tuning feedback current.
- TDAC: tuning of discriminator threshold.
- Local charge injection circuitry.

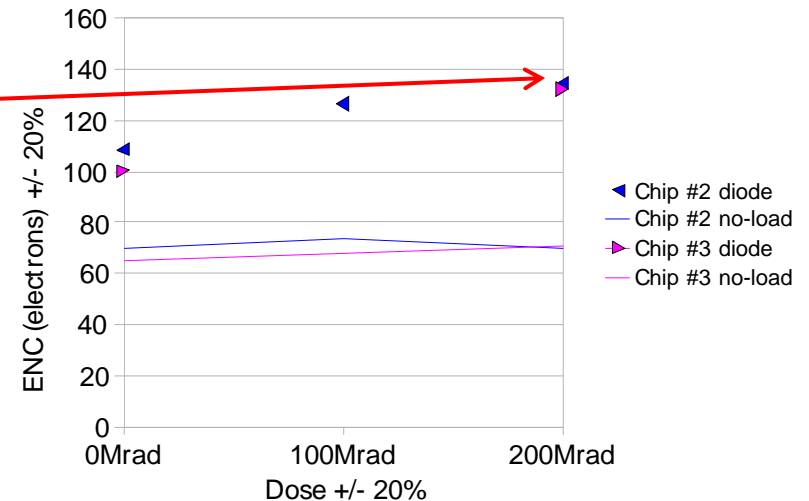
# Analog Pixel: Noise & Irradiation

- Excellent un-tuned threshold dispersion.



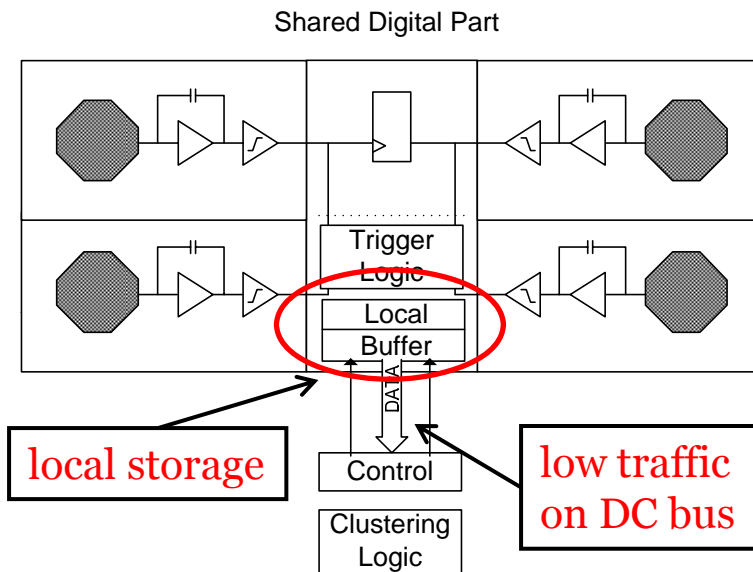
- Dose received: **~200 Mrad** →
- Low I (10  $\mu$ A): noise increases ~20 %.

Low current (which is target value) is 10  $\mu$ A/pixel  
for preamp+amp2+comparator  
Current for minimum noise: 17  $\mu$ A/pixel

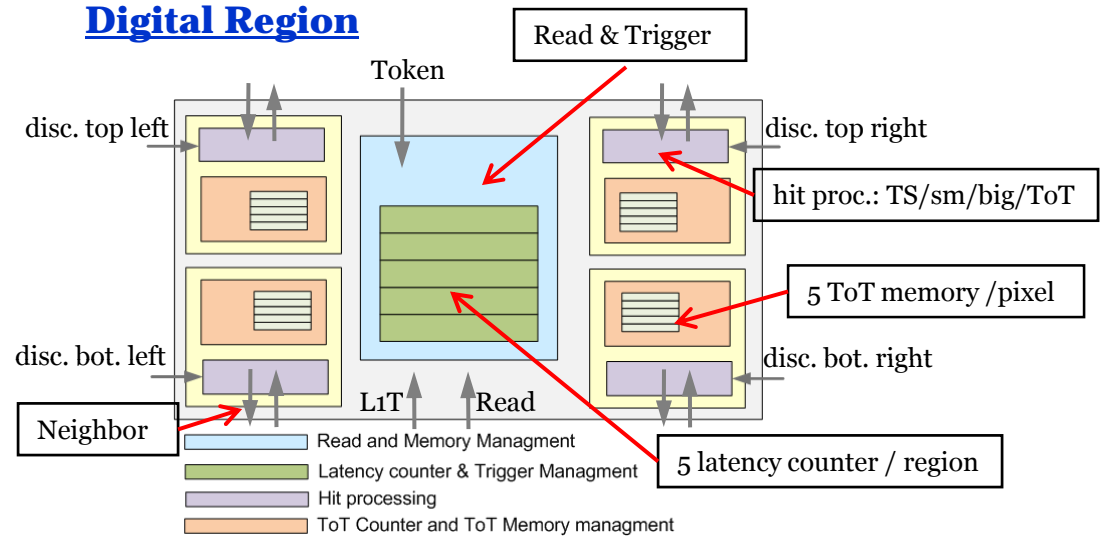


# Digital Pixel: Regional Architecture

## 4-Pixel Unit



## Digital Region



- Store hits locally in region until L1T.
- Only 0.25% of pixel hits are shipped to EoC → DC bus traffic “low”.
- Each pixel is tied to its neighbors -time info- (clustered nature of real hits). Small hits are close to large hits! To record small hits, use position instead of time. Handle on TW.

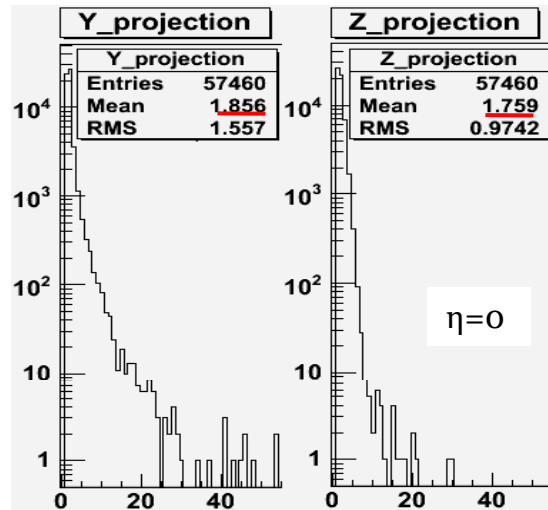
## Consequences:

- Spatial association of digital hit to recover lower analog performance.
- Lowers digital power consumption (below 10  $\mu\text{W}$  / pixel at IBL occupancy).
- Physics simulation → Efficient architecture.



# Performance / Efficiency

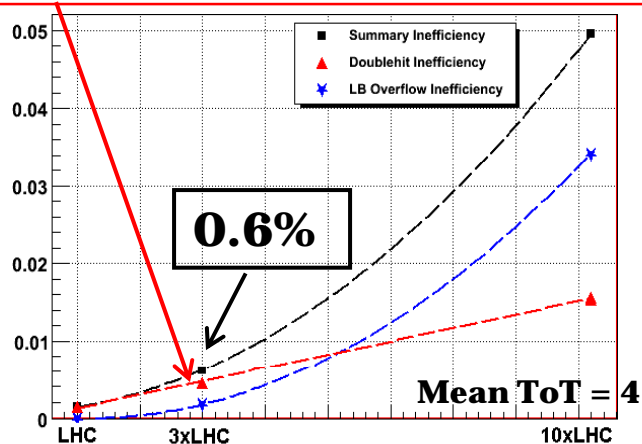
**IBL: charge sharing in Z comparable to phi**



## Regional Buffer Overflow

Memories	Simulation		Analytical	
	IBL	10xLHC	IBL	10xLHC
5	0.047%	2.19%	0.029%	2.25%
6	0.011%	0.65%	0.003%	0.57%
7	<0.01%	0.16%	<0.01%	0.13%

**@ IBL rate, pile-up inefficiency is the dominant source of inefficiency**

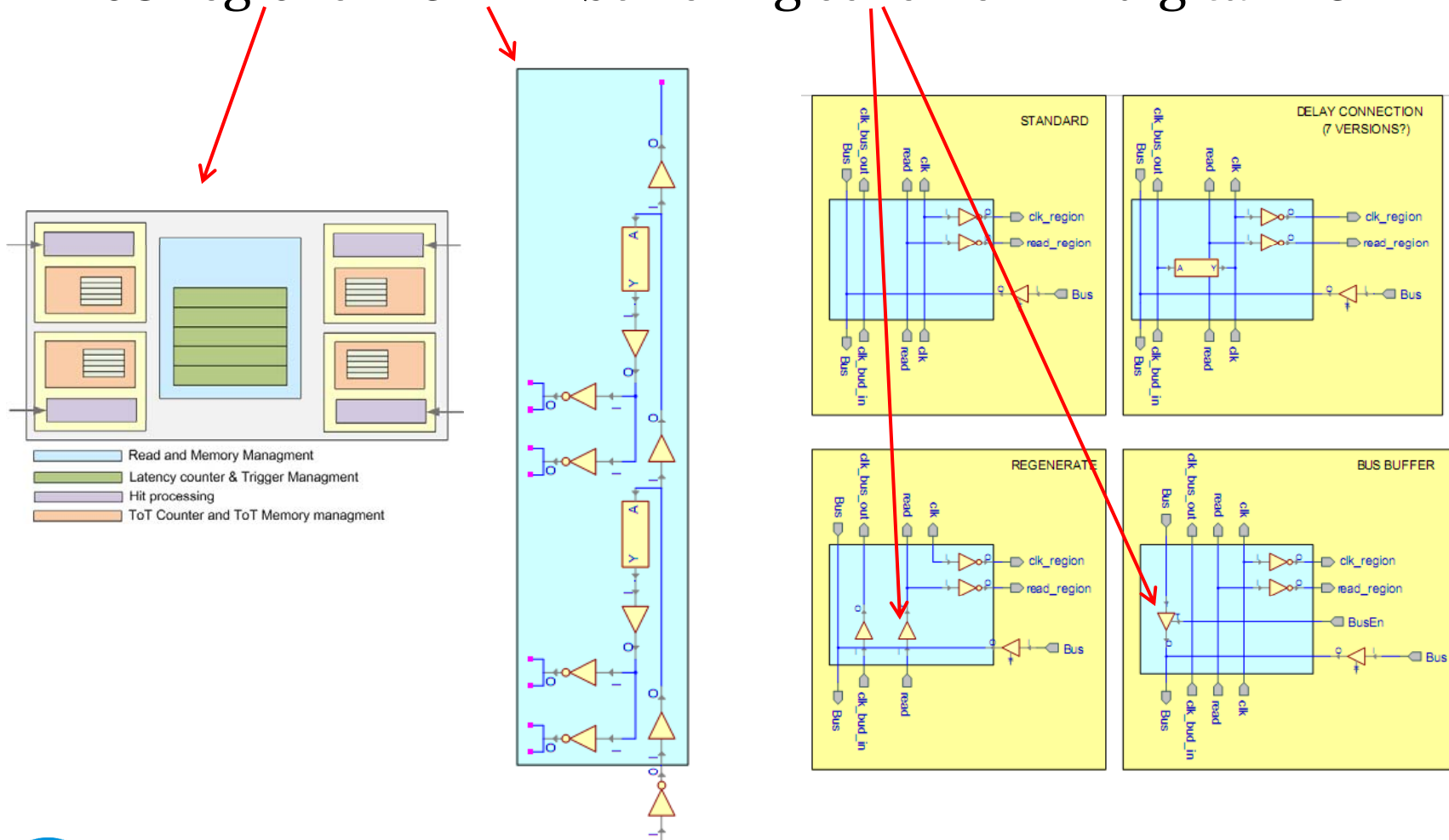


## Inefficiency:

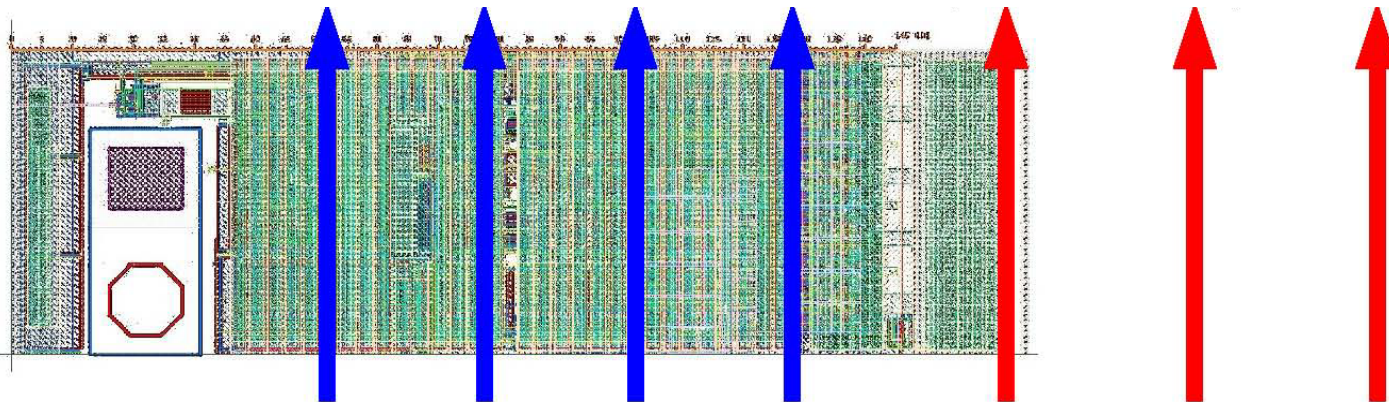
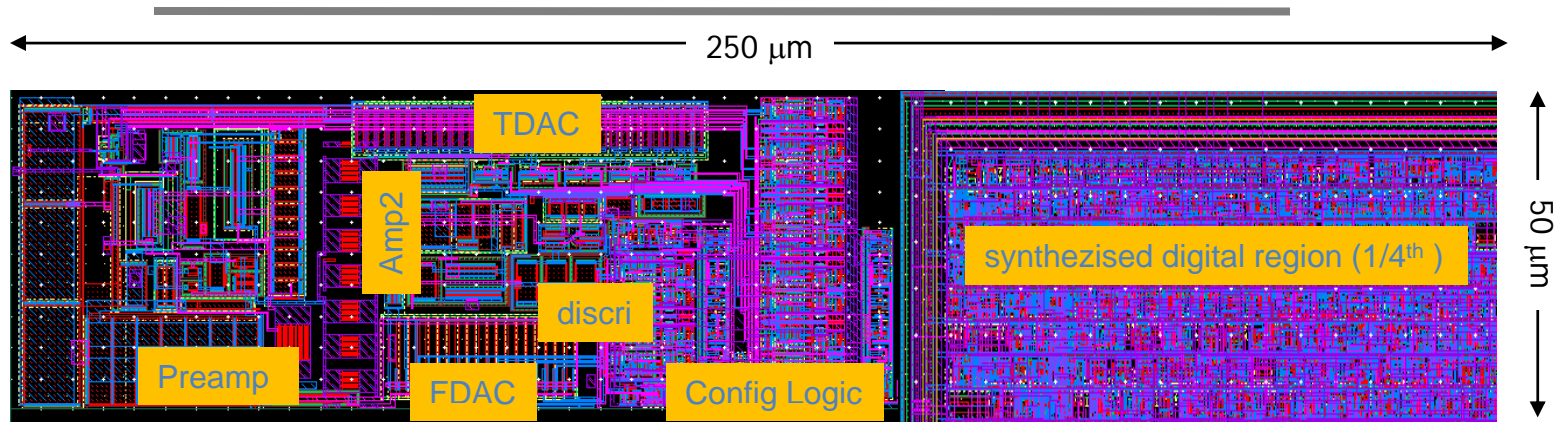
- Pile-up inefficiency (related to pixel x-section and return to baseline behavior of analog pixel)  $\rightarrow \sim 0.5\%$ .
- Regional buffer overflow  $\rightarrow \sim 0.05\%$ .
- **Inefficiency under control for IBL occupancy.**

# Digital Column Architecture

- 168 regions + CLK + buffering scheme → 1 digital DC



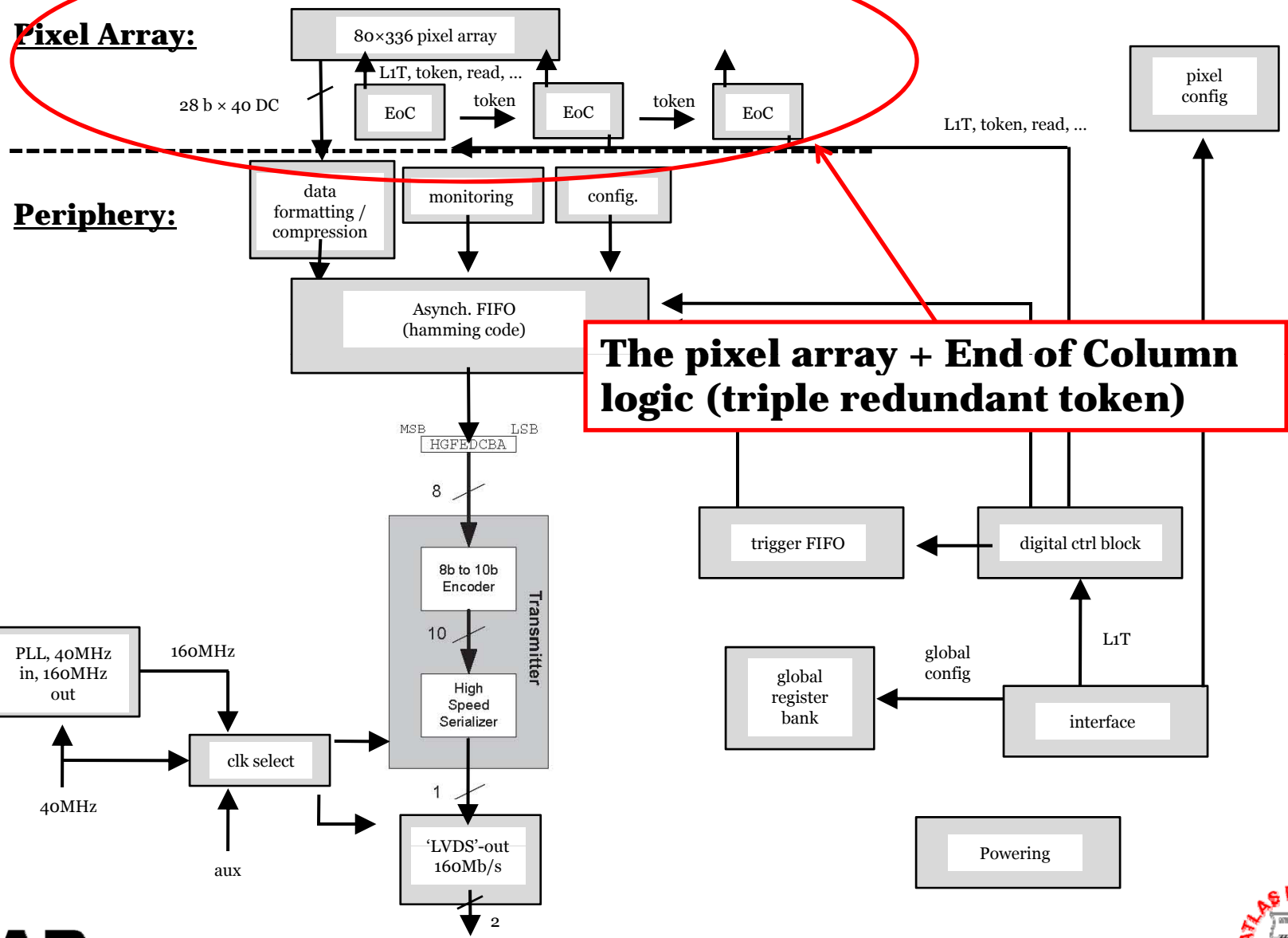
# Pixel Layout



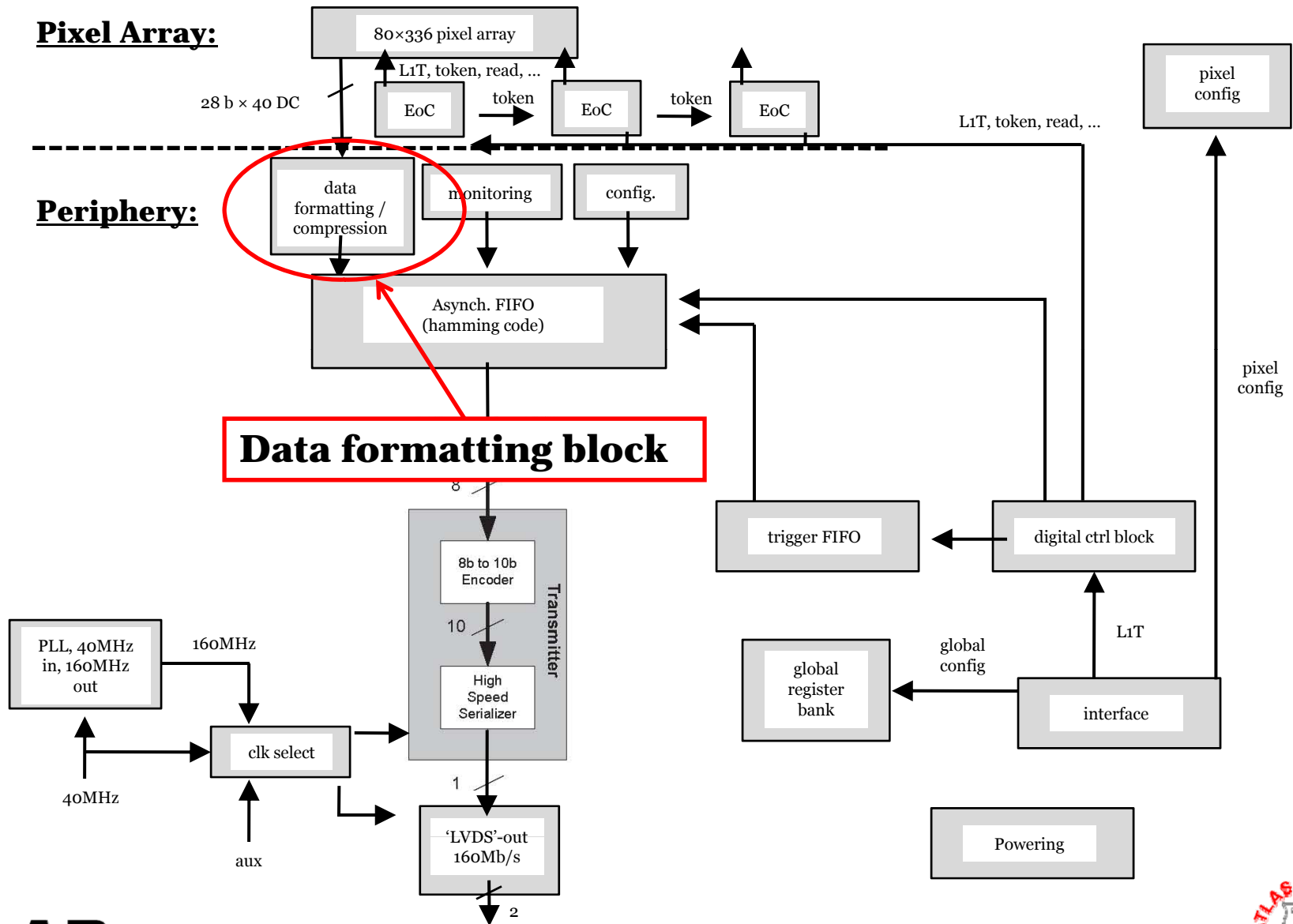
Power distribution and shield on top metals. Only vertical - no analog/digital crossing

Note: Digital ground tied to substrate, mixed signal environment BUT **digital region placed in "T3" deep n-well.**

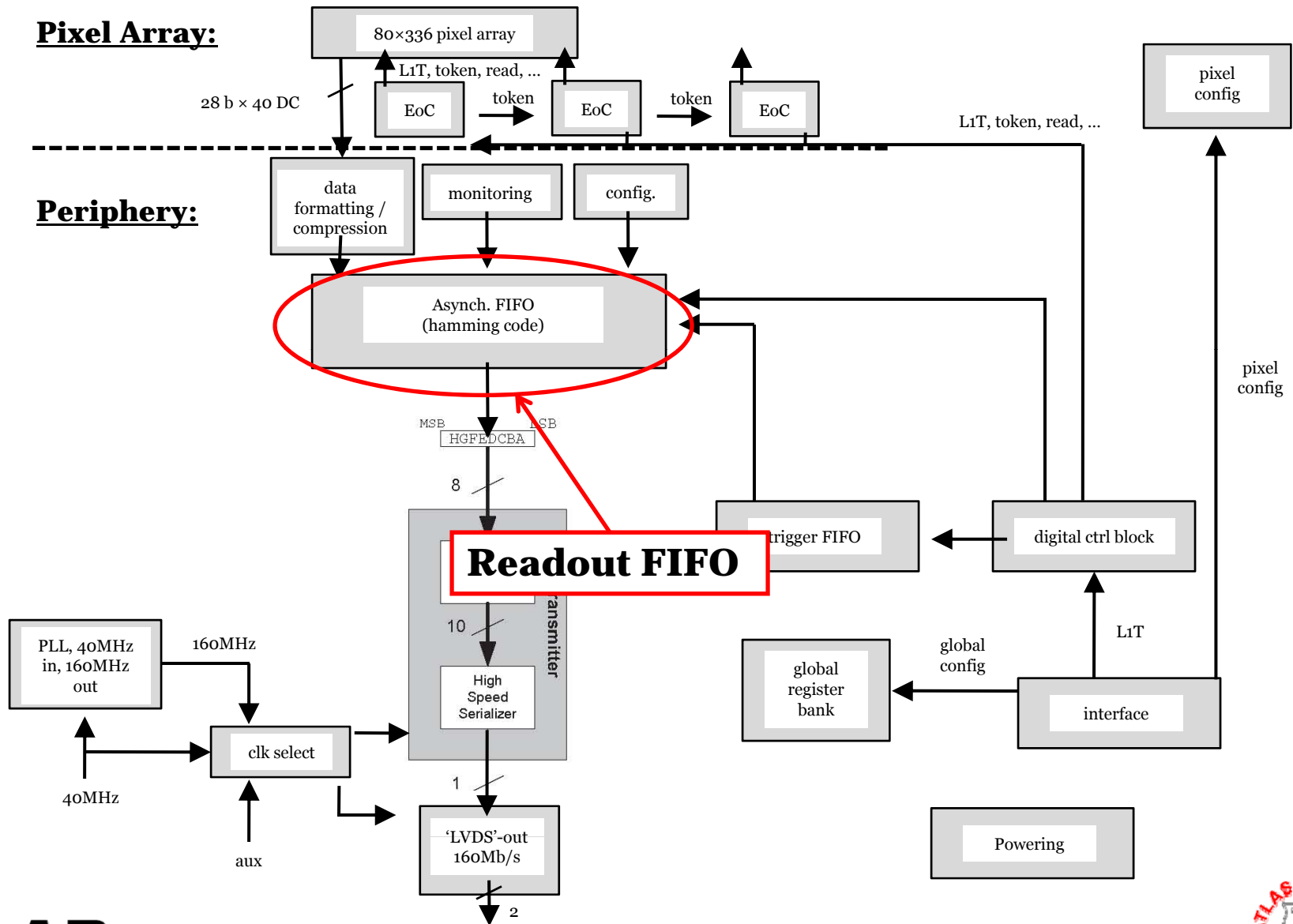
# FE-I4 Periphery



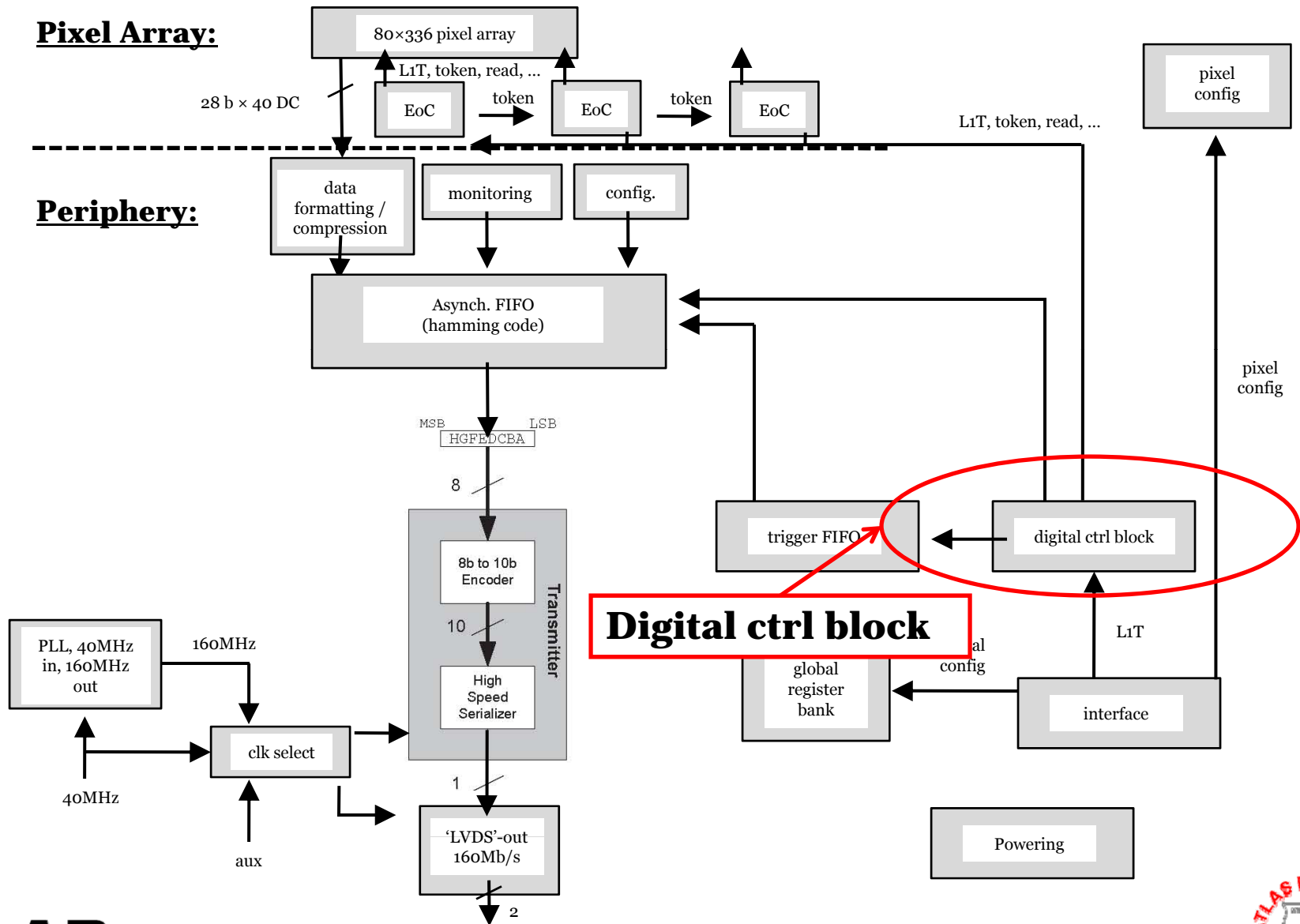
# FE-I4 Periphery



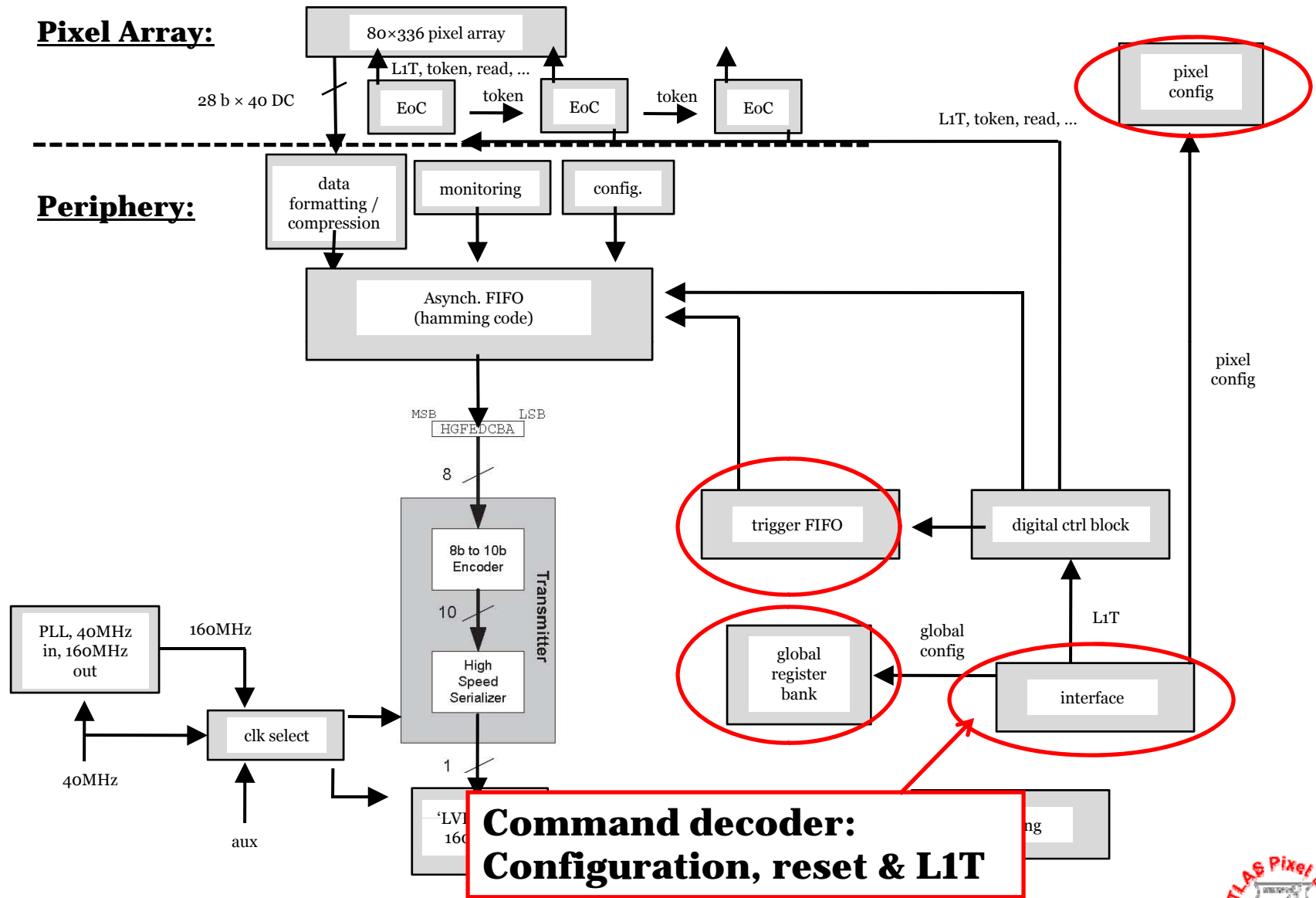
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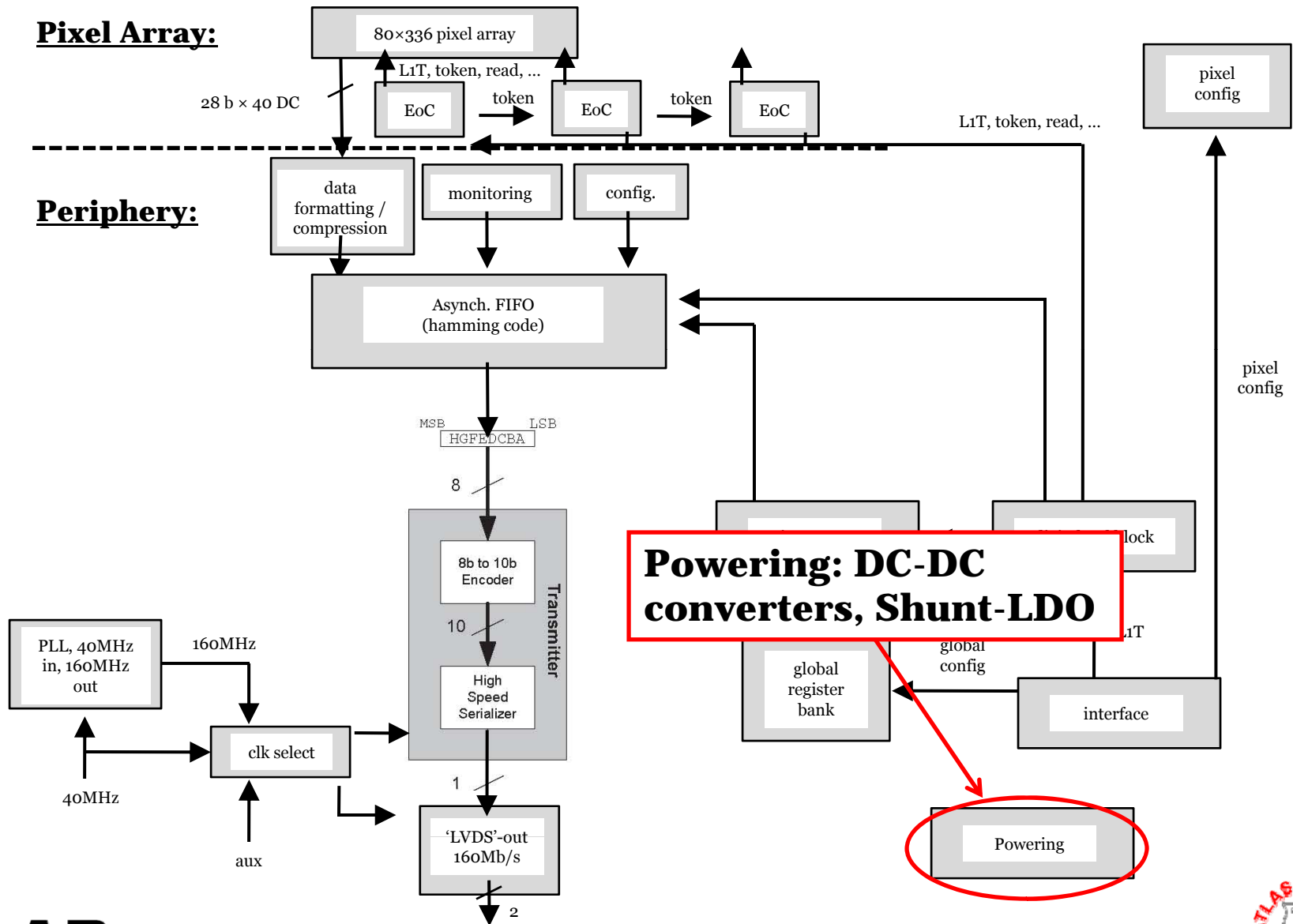


# FE-I4 Periphery

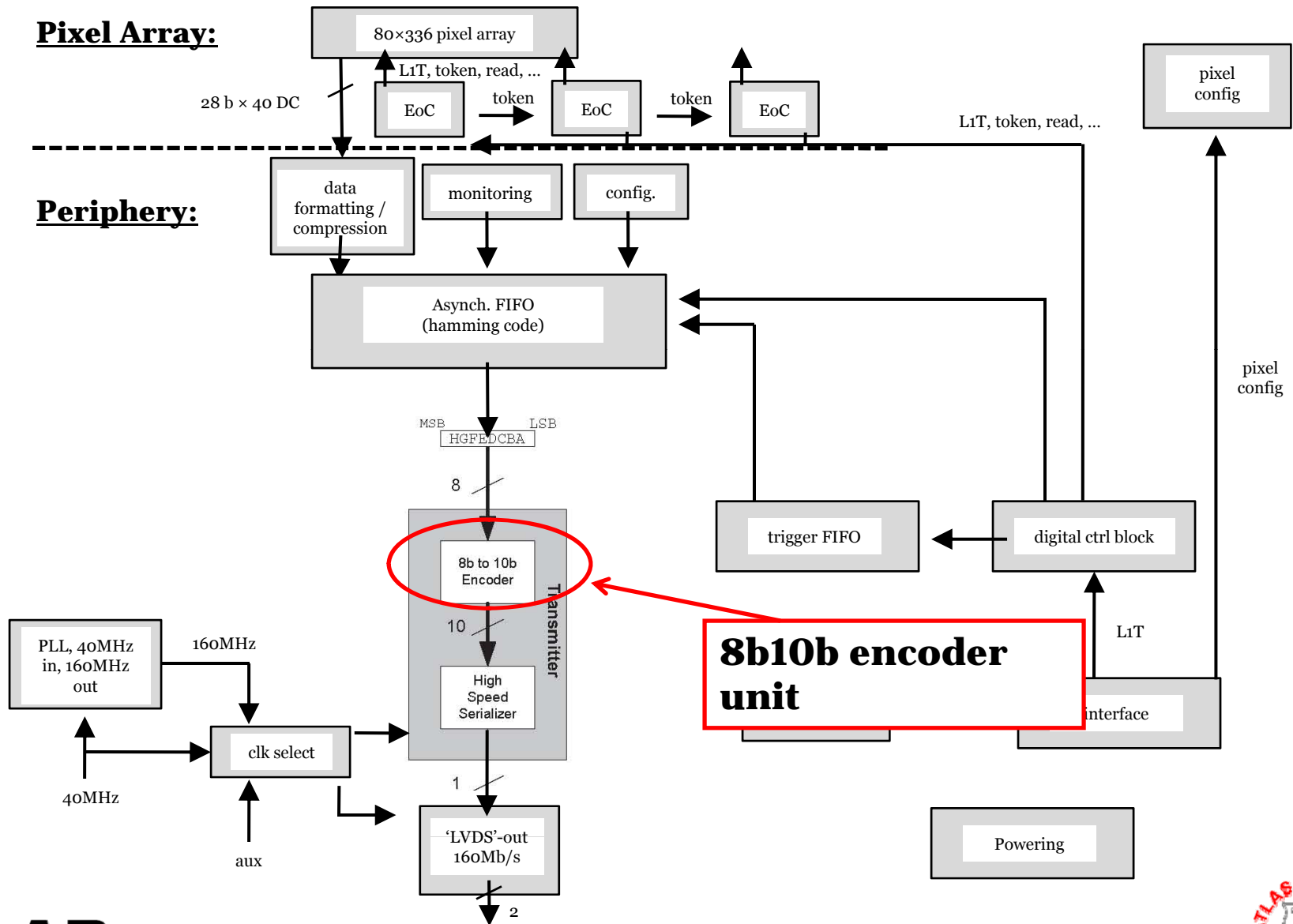




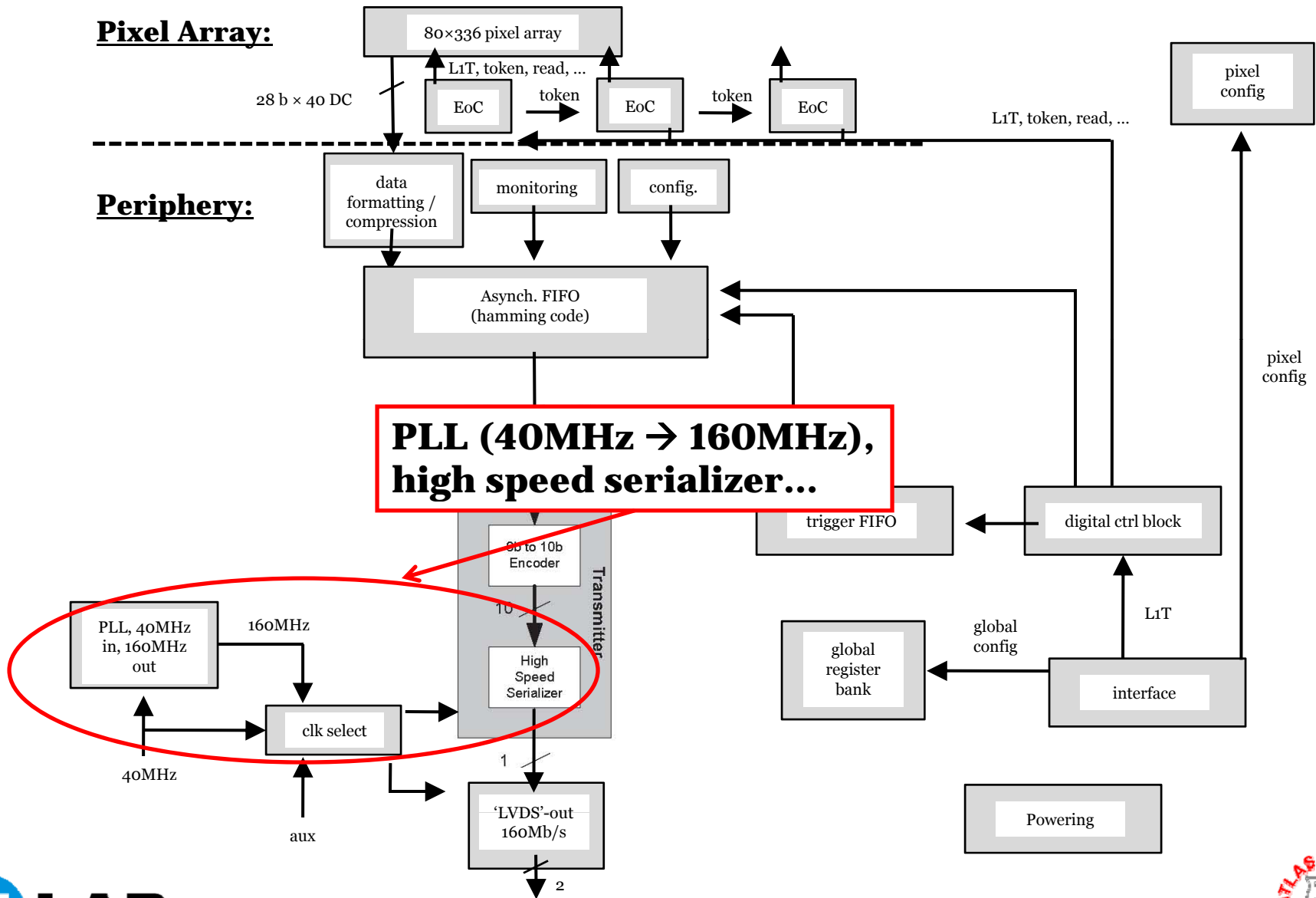
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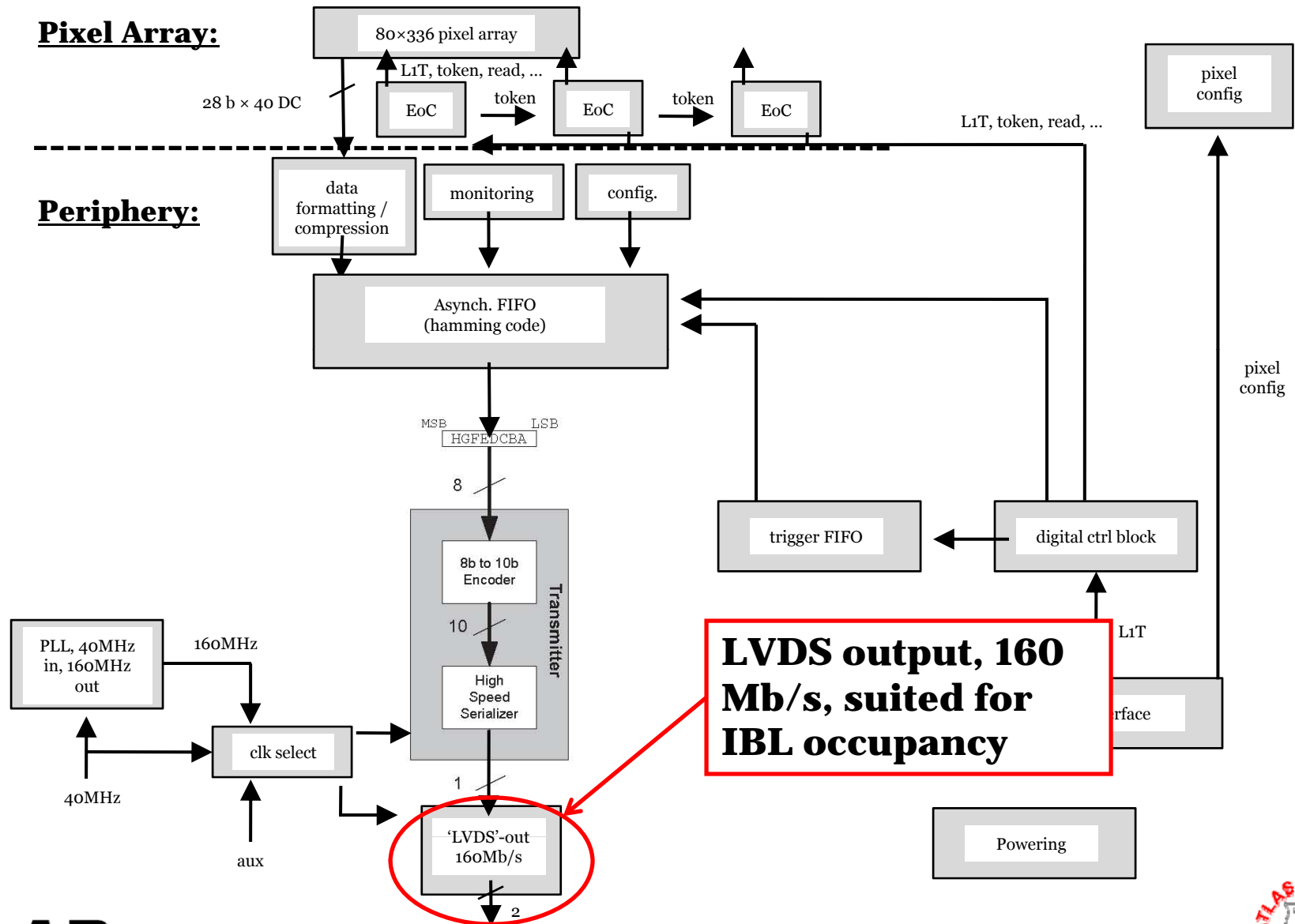
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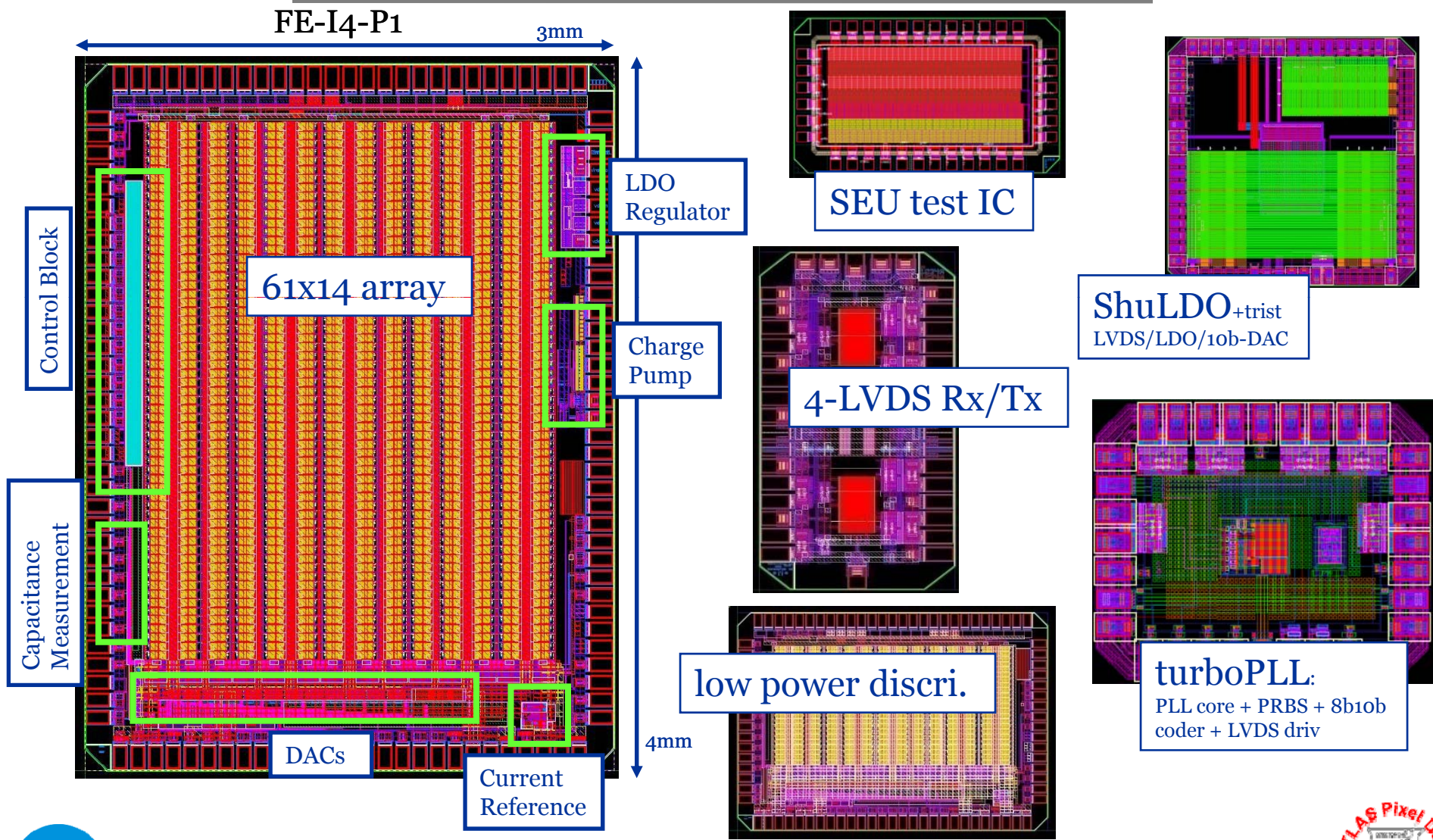


# Yield

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- Estimated from:
  - Small analog test chips.
  - 8 fully tested wafers of Medipix 3 ICs, assuming same defect density for synthesized logic.
- Expect **of order ~39% digitally** perfect chips.
- Yield enhancement:
  - Triple redundant read tokens.
  - Hamming coded pixel data and address (w. minimal # of gates).
  - Redundant configuration shift register.
- → **Fully functional chips yield might be as high as 76%.**  
(with isolated dead pixels at level <0.1%).

# Test Chip Submission



# Schedule and more information

**Schedule:** Submission planned for End 2009  
(submission readiness review 3-4 Nov. 2009)

- Few references:
  - “Development of the ATLAS FE-I4 pixel readout IC for b-layer Upgrade and Super-LHC”, M. Karagounis *et al*, proceedings of TWEPP 2008.
  - “Design and Measurements of SEU tolerant latches”, M. Menouni *et al*, proceedings of TWEPP 2008.
  - “New ATLAS Pixel Front-End IC for Upgraded LHC Luminosity”, M. Barbero *et al*, submitted to Nucl. Instr. Meth. A, Sept. 2008.
  - “Digital Architecture and Interface of the New ATLAS Pixel Front-End IC for Upgraded LHC Luminosity”, D. Arutinov *et al*, IEEE Trans. Nucl. Sci. 56, 388 (2009).
  - “An Integrated Shunt-LDO Regulator for Serial Powered Systems”, M. Karagounis *et al*, Proceedings of the 35th European Solid-State Circuits Conference, 2009.
  - “Charge Pump Clock Generation PLL for the Data Output Block of the Upgraded ATLAS Pixel Front-End in 130 nm CMOS”, A. Kruth *et al*, Proceedings TWEPP 2009.
  - “Low Power Discriminator for ATLAS Pixel Chip”, M. Menouni *et al*, proceedings of TWEPP 2009.
- More information: Poster later this morning  
“Digital Architecture of the new ATLAS Pixel Chip FE-I4” (Session N13, ‘Posters I’  
Location: Grand Ballroom 4 / 5. Oct. 27, 10:30-12:00).

# backup

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# BACKUP SLIDES